

## CinCam Application Laser Line Characterization - CinLine -

The CinLine tool is a compact and unique tool to measure beam profiles of cw and pulsed laser systems from UV to NIR spectral range. This system includes a special designed diffusion screen and the camera-based CinCam CCD/CMOS beam profiler with imaging optic. The sophisticated screen architecture enables speckle-free beam profiling especially of laser lines, rectangle profiles or laser with large beam diameter. Several versions are available to open up new opportunities in laser characterization. The compact measurement system is designed to be used in industry, science, research and development.

- Speckle-free diffusion screen
- Pre-assembled and compact measurement system
- Accurate and reliable measurements
- Compatible with cw and pulsed laser systems
- Measurement data as printable protocol

Spectral response:	320nm – 1150nm
Beam Profiler:	CinCam CMOS / CCD
Input Power (max):	500mW
Input Intensity (max):	10W/cm <sup>2</sup>
Resolution:	Up to 17µm
Interface:	FireWire / USB / GigE

I. Option



Active Area: 30mm x 30mm  
Beam Diameter (max): 20mm x 20mm

II. Option

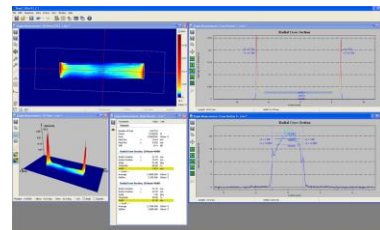


Active Area: 40mm x 20mm  
Beam Diameter (max): 27mm x 13mm

III. Option



Active Area: 60mm x 15mm  
Beam Diameter (max): 40mm x 10mm



### NEW: Line Scan Beam Profiler

- Customized solution (depends on the application)
- Fully automated and fast line beam analysis
- Available with high-resolution CCD / CMOS / InGaAs sensor
- 250-1800nm (depends on sensor)
- Line width, homogeneity, edge steepness, etc.
- Scalable for up to 16x beam profiler
- Variable beam lengths
- Sensitivity correction (multi beam profiler)

